

Zerstörungsfreie Multisensor-Messtechnik für die Analyse von Oberflächen



MicroSpy® Topo
Konfokalmikroskop

Messaufgaben

- Rauheit
- Stufenhöhe
- Profil, Kontur
- Schichtdicke
- Pitch, Trench
- TTV (Total Thickness Variation)
- Bumps
- 3D Topographie
- Bow, Warp
- Koplanarität
- Parallelität
- Winkel
- CD (Critical Dimensions)



MicroProf® Multisensor
Production Tool
Multisensor Messgerät für die Produktionsumgebung



MicroProf® Multisensor
Multisensor Messgerät



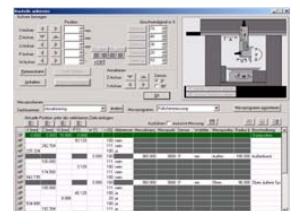
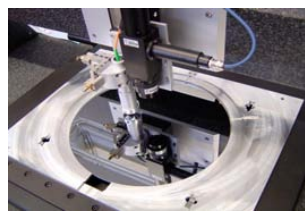
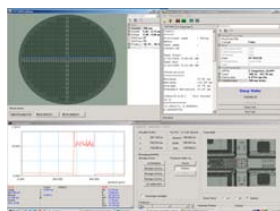
MicroProf® MFE TTV
Vollautomatisches Multisensor Messgerät für die TTV Wafer Inspektion



MicroProf® MFE
Multisensor Bridgetool für die umfassende vollautomatische Inspektion von 200 und 300 mm Wafern. Ausgestattet mit Klasse 1 EFEM und SECS/GEM.

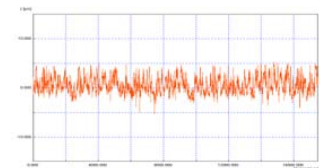
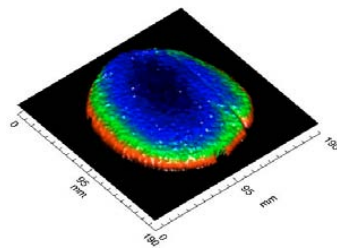
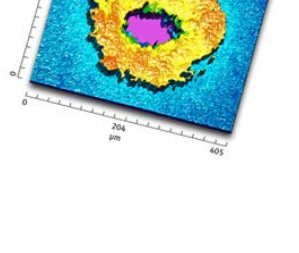
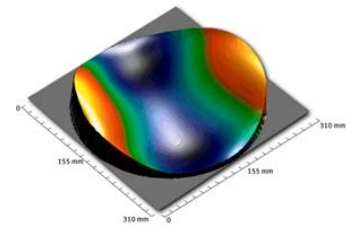
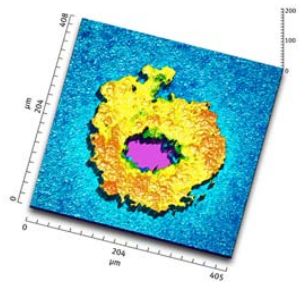
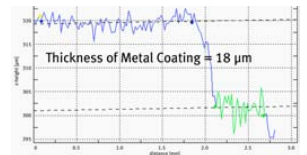
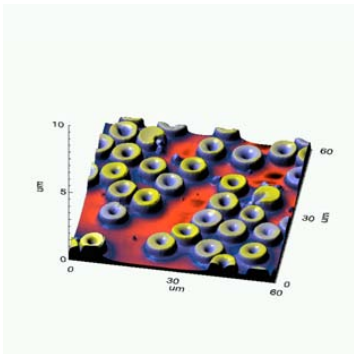
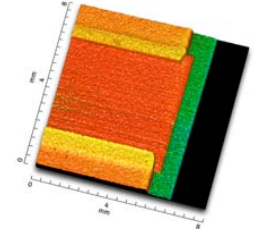
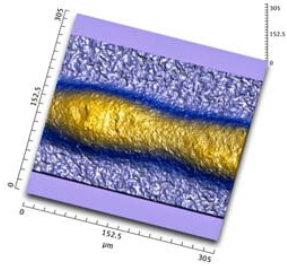
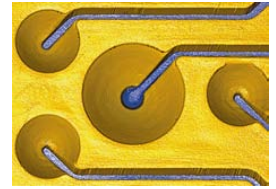
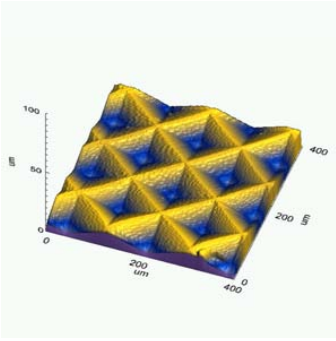
Zielbranchen

- Halbleiter/Mikroelektronik
- MEMS/Mikrostrukturtechnik
- Photovoltaik/Solar
- Optik
- Automotive



Referenzkunden

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Wafer No.	Parameter										Thickness		
	TTV	TIR	LTV	PLTV	LTIR	PLTIR	LFPD	PLFPD	WARP	BOW	Min	Mean	Max
1	2,746	2,719	2,525	100,0	2,515	62,7	-1,472	32,1	1,517	-3,995	607	609	611
2	4,741	4,706	2,746	82,6	2,671	62,7	-1,298	60,9	1,083	6,346	599	603	605
3	15,040	12,866	4,116	0,0	4,109	0,0	3,557	12,7	1,386	-8,540	638	643	655

All values in μm

Ra:	1.257 μm	Rku:	2.647
Rq:	1.527 μm	RPc:	94.392/cm
Rz(ISO):	9.082 μm	RK:	3.792 μm
Rz(DIN):	8.371 μm	Rpk:	1.775 μm
Rmax:	10.098 μm	Rvk:	0.944 μm
Rp:	4.587 μm	Mr1:	17.311 %
Rv:	5.519 μm	Mr2:	95.928 %
Rt:	10.106 μm	V0:	0.019 $\mu\text{m}^3/\mu\text{m}^2$
Rsk:	0.403		

FRT the art of metrology™

Fries Research & Technology GmbH • Friedrich-Ebert-Strasse • D-51429 Bergisch Gladbach
 Tel. +49 (0)2204 - 84 24 30 • Fax. +49 (0)2204 - 84 24 31 • info@frt-gmbh.com • www.frt-gmbh.com